L Number	Hits	Search Text	DB	Time stamp
1	1622	endpoint adj detect$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/08 11:37
8	2	(endpoint adj detect$4) and (intonation or prosody)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/08 11:49
15	19	(endpoint adj detect$4) and (fundamental adj frequency)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/08 11:58
22	128	(endpoint adj detect$4) and pitch	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/08 11:58

L Number	Hits	Search Text	DB	Time stamp
1	1	Lenning-m$.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/03/08 15:56
7	7	beresford-k$.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/03/08 15:58
13	4	peckham-j$.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/03/08 15:59
19	1	frangoulis-e$.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/03/08 15:59
25	602	thomas-t$.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/03/08 16:00
31	7	thomas-t$.in. and (end adj point)	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/03/08 16:01

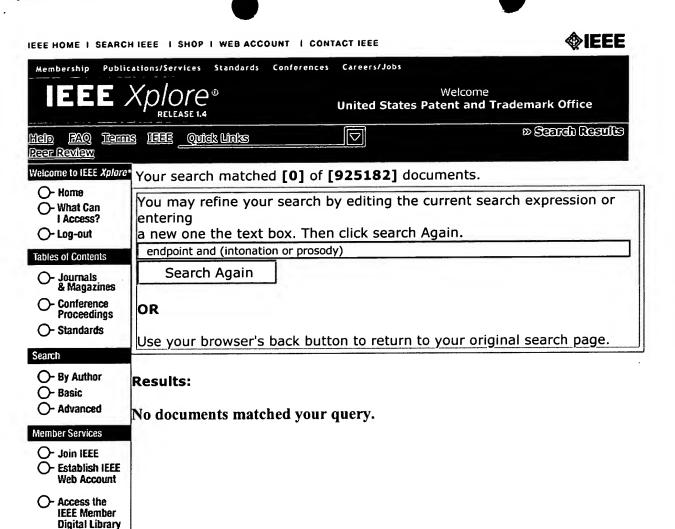| L Number	Hits	Search Text	DB	Time stamp
1	112	704/241.ccls.	USPAT	2003/03/08 17:22
2	59	704/241.ccls. and (endpoint or (end adj point))	USPAT	2003/03/08 17:30
3	12	(704/241.ccls. and (endpoint or (end adj point))) and syllable	USPAT	2003/03/08 17:30

L Number	Hits	Search Text	DB	Time stamp
1	81131	endpoint or (end adj point)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/08 16:11
8	43	(endpoint or (end adj point)) and ((duration or time) with (syllable))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/08 16:33
15	5066	(endpoint or (end adj point)) and ((fundamental adj frequency) or pitch)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/08 16:34
22	70	((endpoint or (end adj point)) and ((fundamental adj frequency) or pitch)) and syllable and time	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/08 16:55
29	52	((endpoint or (end adj point)) and ((fundamental adj frequency) or pitch)) and intonation	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/08 17:06

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